

**Search Notes**

Application/Control No.

10/608,761

Examiner

Le Nguyen

Applicant(s)/Patent under  
Reexamination

WIEROWSKI, JAMES V.

Art Unit

2174

**SEARCHED**

Class	Subclass	Date	Examiner
715	712	9/30/2007	LVN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
US-PG Pub, USPAT: 715/712		9/30/2007	LVN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
US-PG Pub, USPAT: 715/712, 734, 738, 739, 805, 838, 850- 855, 513; 701/201, 208, 210; 705/26, 27	9/22/2007	LVN